

微分析MuAnalysis

微電子及光電元件診斷分析服務領導者

微電子技術服務一覽

我們協助設計師及製造業

- ◎ 縮短設計週期
- ◎ 減少用戶退貨
- ◎ 達到最高產品利潤

微分析提供電子、微電子及光電企業界專業分析診斷師及先進實驗室之服務。我們的專業科學家及一流高級設備被證實我們為客戶省錢省時間的良好記錄。

微分析診斷服務縮短設計週期

微分析的科技分析團隊有數十年半導體設計、製造和組裝技術的豐富經驗。我們受過優質訓練的分析員能夠鑑定評估多類型的元件、封裝及製程技術。微分析的科技分析團隊擅長於故障分析、利潤分析、材料分析及可靠性測試。

微分析可靠性測試減低用戶退貨率

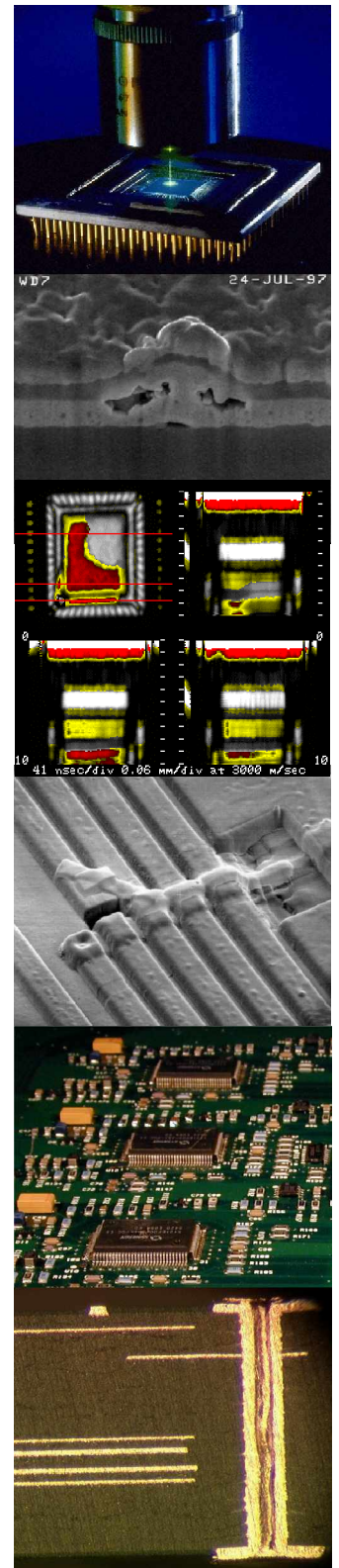
微分析之可靠性測試技術分析各類元件足以比照一系列的商用及軍用標準運作程序。當可靠性測試中斷，我們在職分析服務員會快速的確認故障原因及提供維修處理，讓測試繼續維持運作。

微分析對製造業的支持與服務達到最高產品利潤

微分析對製造業的協助服務團員均有豐富的 Silicon, GaAs 及 InP processes 等元件製程經驗。以一個獨立專業家，我們能夠處理你與你供應商之間的關係。

專業與保密性服務

微分析服務以發揮最高效率為主，有些服務 48 小時即可完成。按客戶要求可以提供最精確的書面報告。所有的微分析服務以高度保密，監控設備及絕不向外透露客戶機密為原則。



muanalysis.com

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MuAnalysis Technical Services Description

MuAnalysis Analytical Services

Scanning Electron Microscopy (SEM)

- Digital imaging
- Elemental chemical analysis by EDX
- Sub-micron thin film measurements
- Process monitoring
- Construction analysis

Materials Analysis

- Raman micro-spectroscopy
- FTIR micro-spectroscopy
- Confocal Laser Scanning microscopy
- UV fluorescence imaging
- Microcontamination analysis

Laser Materials Processing

Applications:

- Deposit metal conductors
- Polyimide ablation
- Laser cutting

Failure Analysis Capabilities

- Construction analysis – package, structures and process definition
- Yield and process defect analysis
- X-ray radiography
- Scanning acoustic microscopy
- Decapsulation and package opening
- Precision cross sectioning, delayering, staining, and chemical techniques
- Plasma etching
- Automated latch-up and curve trace testing
- Precision mechanical electrical probing
- RF Microprobing
- Liquid crystal fault isolation
- Fluorescent microthermal imaging
- Voltage contrast analysis
- Emission microscopy / Optical Beam Induced Current (OBIC) analysis
- Infra-red (IR) optical microscopy
- High-resolution optical microscopy
- Dynamic Electroluminescence Imaging (DEI)

MuAnalysis Reliability Testing

Tests

- Electrostatic Discharge (ESD)
- Latch-up
- Temperature humidity bias
- Highly Accelerated Stress Test (HAST)
- Autoclave
- High temperature storage
- Burn-in/Life test, static or dynamic
- Power Cycling
- Solderability
- Preconditioning
- Mechanical shock
- Vibration
- Thermal cycling and thermal shock

Failure Mechanism Specific Testing

- Electromigration
- Time Dependent Dielectric Breakdown (TDDB)
- Assembly/Packaging Assessments
- Reballing

MuAnalysis Consulting Services

MuAnalysis provides materials, reliability and failure analysis consulting services to electronics companies, including:

- Qualification program definition
- Vendor /supplier assessments
- Design consultations for reliability/FA
- Data analysis
- Reliability monitoring
- Yield improvement consulting
- Fab support services
- ESD audits
- Customized seminars/educational programs
- Documentation and formal reports

Other services, tests and diagnostic techniques are available. Please enquire.

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